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E FIELD ESTIMATION DURING BEAM TIME

PROTODUNE DRA MEETING - 4TH JUNE 2019

INTRODUCTION

- Instabilities on the cathode voltage due to HV noise filter problems
- Filter issue understood and a new design is under test: system much more stable even if some (others) instabilities remain

Hardware Performance: HV Ripple Noise **Filters**

- Low pass filter, reduce ~35kHz ripple noise from PS switching frequency
- ProtoDUNE used a "pipe-style" break in the cable to introduce the resistor
 - The resistor is submerged in mineral oil to prevent breakdown in air pockets
 - Containers leak and need often interventions to refill with mineral oil
 - When dry, the filter introduced current spikes and instabilities



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22 June 4, 2019 ProtoDUNE: Lessons Learnt From Beam and Stability Runs



Main focus of today's talk: Impact of HV instabilities on the E-filed?

- Especially important during beam time
- E field value needs to be defined for the next MCC production

INTRODUCTION

Beam summary plot



Drift Efield plot clearly show the instabilities encountered during the beam period

• Efield calculation is wrong : assuming a wrong value for the full circuite resistance

DRIFT DISTANCE DEFINITION

 $d_{C-APA_{Frame}} = 3597 \ mm$ at Room T, from CERN-NP/Benoit's 3D model and PSL/Dan's drawings



THE PROTODUNE CIRCUIT

Values are from the precise measurements performed recently (AFTER the beam)



DEDUCE THE CIRCUIT AT THE TIME OF THE BEAM

What we need to determine is the Voltage at the cathode (?) at the time of the beam runs



E FIELD ESTIMATION DURING BEAM PERIOD



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SOME CONSIDERATIONS

- Damage to the HV filters cannot be attributed to a unique event. A degradation in time is the most plausible assumption
- The E field should then be estimated at the time of the runs. Degradation due to the filters damage is expected
- The Power Supply currently in use is NOT the one used at the time of the beam. The difference in stability from the two PS can be added as a systematic uncertainty to the Efield estimation